

# Dialog DataStar



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## Advanced Search:

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No.	Database	Search term	Info added since	Results	
1	INZZ	wafer OR semicondudor OR chip OR substrate OR IC OR intergrated ADJ circuit	unrestricted	339686	<a href="#">show titles</a>
2	INZZ	L1 AND (detecting OR determine) AND (defect OR flaw OR fault OR reject) AND repetitive AND non ADJ repetitive AND (area OR region)	unrestricted	0	-
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5	INZZ	L1 AND cerating AND (1D OR one AND dimensional OR 1-D) AND (cell OR array OR matrix)	unrestricted	0	-
6	INZZ	L1 AND (1D OR one AND dimensional OR 1-D) AND (cell OR array OR matrix)	unrestricted	14	<a href="#">show titles</a>
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